Abstracts

Microwave Measurement of Conductivity and Permittivity of Semiconductor Spheres by Cavity Perturbation Technique

A. Mansingh and A. Parkash. "Microwave Measurement of Conductivity and Permittivity of Semiconductor Spheres by Cavity Perturbation Technique." 1981 Transactions on Microwave Theory and Techniques 29.1 (Jan. 1981 [T-MTT]): 62-65.

Simple analytical relations for evaluating the components of complex relative permittivity of semiconductors using a cavity perturbation technique for spherical samples are presented. The relations although derived under a simplifying approximation yield remits of almost the same accuracy obtained by computer solutions of a transcendental equation for samples with resistivity up to about 1 Omega-cm.

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